SGM42560Q
Automotive 16V, 2.5A Three-Phase Integrated FET Motor Driver

GENERAL DESCRIPTION

The SGM42560Q is a triple half-bridge driver, which is designed to drive three-phase brushless DC motors. The device integrates three current sense amplifiers (CSA) for sensing the three phase currents of BLDC motor.

For SGM42560Q, the ENx and PWMx control inputs are provided for each half-bridge. The required high-side gate drive voltages are generated by an internal charge pump.

The device has multiple protection functions, including under-voltage lockout (UVLO), over-current protection (OCP) and thermal shutdown (TSD). The nFAULT pin is used to indicate the fault problems.

The device is AEC-Q100 qualified (Automotive Electronics Council (AEC) standard Q100 Grade 1) and it is suitable for automotive applications.

The SGM42560Q is available in a Green TQFN-3×4-24L package.

FEATURES

- **AEC-Q100 Qualified for Automotive Applications**
  Device Temperature Grade 1
  T_A = -40℃ to +125℃
- **Operating Supply Voltage: 3V to 16V**
- **High Output Current Capability**
  - **2.5A Continuous Current**
  - **5A Peak Current**
- **On-Resistance: 185mΩ (HS + LS) at +25℃**
- **Control Inputs: ENx and PWMx**
- **Integrated Low-side Current Sensing**
- **Built-in LDO Regulator: 3.3V, 50mA**
- **Supports 100% PWM Duty Cycle Driving**
- **Automatic Synchronous Rectification**
- **Integrated Protection Features**
  - **Under-Voltage Lockout (UVLO)**
  - **Over-Current Protection (OCP) with Adjustable Threshold**
  - **Thermal Shutdown (TSD)**
- **Available in a Green TQFN-3×4-24L Package**

APPLICATIONS

Three-Phase BLDC Motor Drivers

TYPICAL APPLICATION

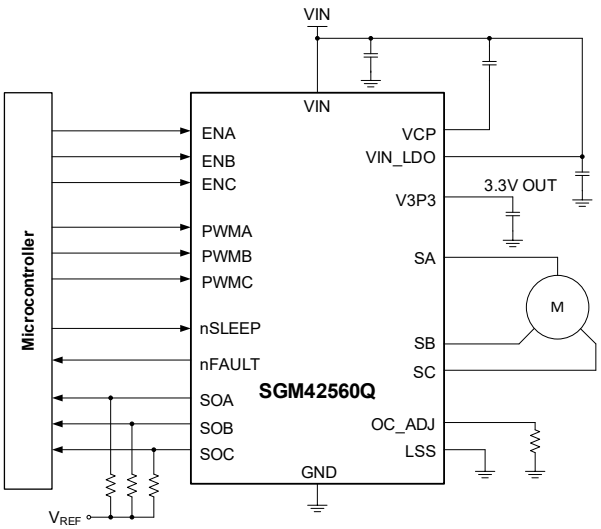


Figure 1. Typical Application Circuit

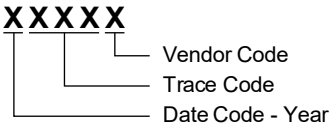
代理商 威尔迈 www.visvie.com 联系电话 138 2526 5270

PACKAGE/ORDERING INFORMATION

MODEL	PACKAGE DESCRIPTION	SPECIFIED TEMPERATURE RANGE	ORDERING NUMBER	PACKAGE MARKING	PACKING OPTION
SGM42560Q	TQFN-3×4-24L	-40℃ to +125℃	SGM42560QTRR24G/TR	262 XXXXX	Tape and Reel, 4000

MARKING INFORMATION

NOTE: XXXXX = Date Code, Trace Code and Vendor Code.



Green (RoHS & HSF): SG Micro Corp defines "Green" to mean Pb-Free (RoHS compatible) and free of halogen substances. If you have additional comments or questions, please contact your SGMICRO representative directly.

ABSOLUTE MAXIMUM RATINGS

Supply Voltage, V_{IN}, V_{IN_LDO} ..... -0.3V to 18V
V_{Sx} ..... -0.3V to V_{IN} + 0.3V
V_{CP} ..... -0.3V to V_{IN} + 5V
GND to LSS ..... -0.3V to 0.3V
Voltage at All Other Pins ..... -0.3V to 5V
Package Thermal Resistance
TQFN-3×4-24L, θ_{JA} ..... 31℃/W
TQFN-3×4-24L, θ_{JB} ..... 9℃/W
TQFN-3×4-24L, $\theta_{JC\ (TOP)}$ ..... 26.1℃/W
TQFN-3×4-24L, $\theta_{JC\ (BOT)}$ ..... 2.2℃/W
Junction Temperature ..... +150℃
Storage Temperature Range ..... -65℃ to +150℃
Lead Temperature (Soldering, 10s) ..... +260℃
ESD Susceptibility (1) (2)
HBM ..... ±4000V
CDM ..... ±1000V

NOTES:

1. For human body model (HBM), all pins comply with AEC-Q100-002 specification.
2. For charged device model (CDM), all pins comply with AEC-Q100-011 specification.

RECOMMENDED OPERATING CONDITIONS

Supply Voltage, V_{IN}, V_{IN_LDO} ..... 3V to 16V
Externally Applied PWM Frequency, f_{PWM} ..... 0kHz to 200kHz
Operating Ambient Temperature Range ..... -40℃ to +125℃
Operating Junction Temperature Range ..... -40℃ to +150℃

OVERSTRESS CAUTION

Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect reliability. Functional operation of the device at any conditions beyond those indicated in the Recommended Operating Conditions section is not implied.

ESD SENSITIVITY CAUTION

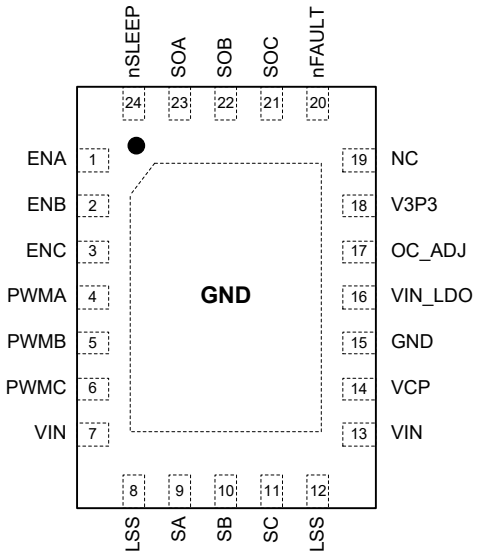
This integrated circuit can be damaged if ESD protections are not considered carefully. SGMICRO recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because even small parametric changes could cause the device not to meet the published specifications.

DISCLAIMER

SG Micro Corp reserves the right to make any change in circuit design, or specifications without prior notice.

PIN CONFIGURATION

(TOP VIEW)



TQFN-3×4-24L

PIN DESCRIPTION

PIN	NAME	FUNCTION
1	ENA	Phase A Enable Input.
2	ENB	Phase B Enable Input.
3	ENC	Phase C Enable Input.
4	PWMA	Phase A PWM Input.
5	PWMB	Phase B PWM Input.
6	PWMC	Phase C PWM Input.
7, 13	VIN	Supply Voltage. Connect at least one 0.1μF ceramic capacitor between VIN and GND, placing it as close as possible to the VIN pin.
8, 12	LSS	Low-side Source Connection. Directly connected to GND.
9	SA	Output of Phase A.
10	SB	Output of Phase B.
11	SC	Output of Phase C.
14	VCP	Charge Pump Output. Decouple with a 1μF ceramic capacitor to VIN pin.
15	GND	Ground.
16	VIN_LDO	Input Supply Voltage for V3P3 LDO. Recommended to connect directly to VIN. Connect at least one 0.1μF ceramic capacitor to GND, placing it as close as possible to the VIN_LDO pin.
17	OC_ADJ	Adjustable Over-Current Threshold.
18	V3P3	3.3V Voltage Regulator Output. A 4.7μF ceramic capacitor is used between V3P3 and GND pins.
19	NC	No Connection. Not internally connected.
20	nFAULT	Fault Even Indication Pin. Go logic low when a fault occurs. Open-drain output.
21	SOC	Phase C Current Sense Output.
22	SOB	Phase B Current Sense Output.
23	SOA	Phase A Current Sense Output.
24	nSLEEP	Sleep Mode Input. Active-low sleep mode logic input with weak internal pull-down. Apply high to enable device, and low to enter into the low power sleep mode.
Exposed Pad	GND	Ground.

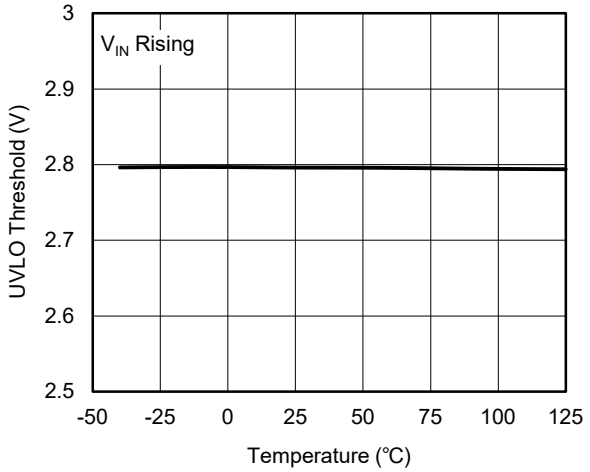
ELECTRICAL CHARACTERISTICS

(T_A = -40℃ to +125℃, V_{IN} = 10V, LSS = GND = 0V, typical values are measured at T_A = +25℃, unless otherwise noted.)

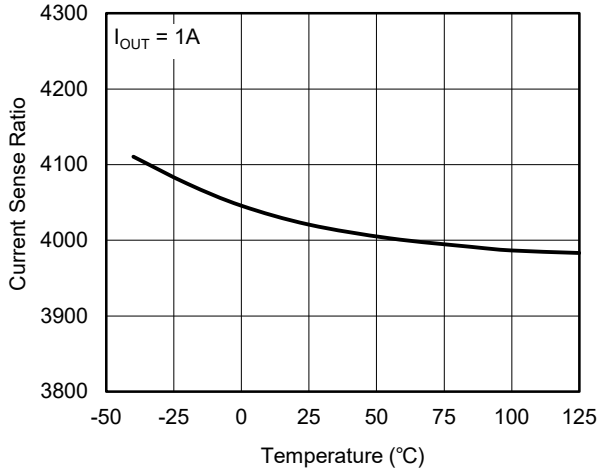
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
Power Supply						
Input Supply Voltage	V_{IN}, V_{IN_LDO}		3		16	V
Quiescent Current	I_Q	nSLEEP = high, ENx = low		2.8	3.6	mA
	I_{nSLEEP}	nSLEEP = low		45	75	μA
Control Logic						
Input Low Threshold	V_{IL}				0.4	V
Input High Threshold	V_{IH}		1.5			V
Logic Input Current	I_{INH}	V_{IN} = 5V	-20		20	μA
	I_{INL}	V_{IN} = 0V	-20		20	μA
Power-Up Delay	t_{PUD}	At V_{IN} rising or nSLEEP rising		0.8		ms
Internal Pull-Down Resistance	R_{PD}	All logic inputs		500		kΩ
nFAULT Pull-Down R_{ON}	R_{ON_nFAULT}			5		Ω
V3P3 Regulator						
V3P3 Pin Voltage	V_{V3P3}	I_{OUT} = 0mA to 50mA	3.3	3.47	3.65	V
Protection Circuits						
UVLO Threshold	V_{UVLO}	V_{IN} rising	2.64	2.8	2.95	V
UVLO Hysteresis	ΔV_{UVLO}			200		mV
OCP Threshold	I_{OCP}	R_{OCP} = 0Ω	2.3	3.5	5.2	A
		R_{OCP} = floating	3.7	6.0	9.0	A
OCP Deglitch Time	t_{OCD}			1.4		μs
Thermal Shutdown Threshold	T_{SD}	Rising		155		℃
Thermal Shutdown Hysteresis	T_{HYS}			30		℃
Current Sense						
Current Sense Ratio			1/3600	1/4000	1/4400	A/A
Current Sense Output Current		T_A = +25℃, LS FET current = 1A	230	250	270	μA
		T_A = +25℃, LS FET current = -1A	-270	-250	-230	μA
		T_A = +25℃, LS FET current = 100mA	19	25	31	μA
		T_A = +25℃, LS FET current = -100mA	-31	-25	-19	μA
Current Sense Output Voltage Swing		LS FET current = ±0.25A	0.05		3.7	V
Output						
HS FET On-Resistance	R_{DSON}	I_{OUT} = 1A	35	90	160	mΩ
LS FET On-Resistance		I_{OUT} = 1A	35	95	165	
Output Rise Time	t_R	R_{LOAD} = 50Ω		25		ns
Output Fall Time	t_F	R_{LOAD} = 50Ω		25		ns
Dead Time	t_D	R_{LOAD} = 50Ω		40		ns
PWMx to Sx Delay Time Rising	t_{DLY_R}			70		ns
PWMx to Sx Delay Time Falling	t_{DLY_F}			90		ns
Charge Pump						
Charge Pump Output Voltage	V_{CP}			V_{IN} + 3.7		V

TYPICAL PERFORMANCE CHARACTERISTICS

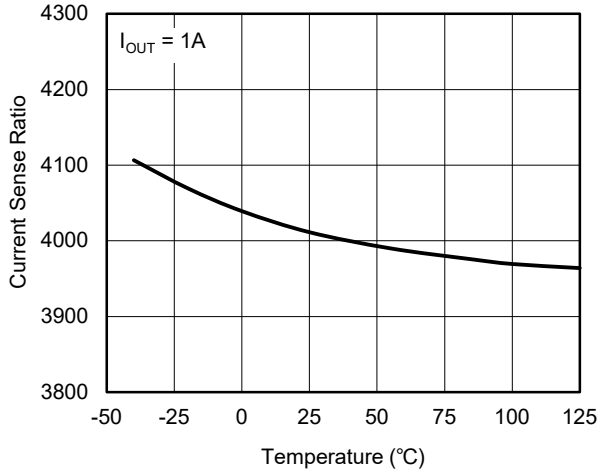
UVLO Threshold vs. Temperature



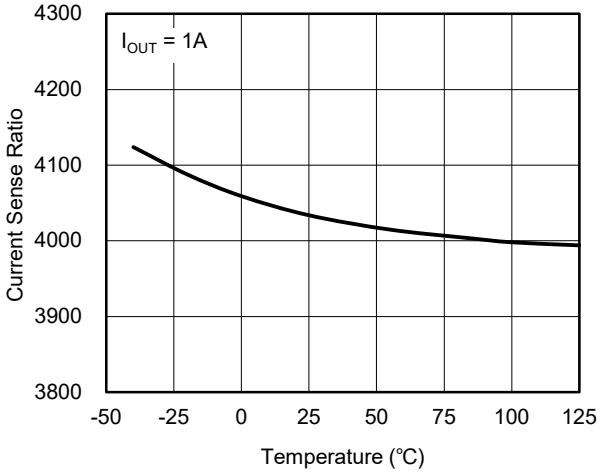
Phase A Current Sense Ratio vs. Temperature



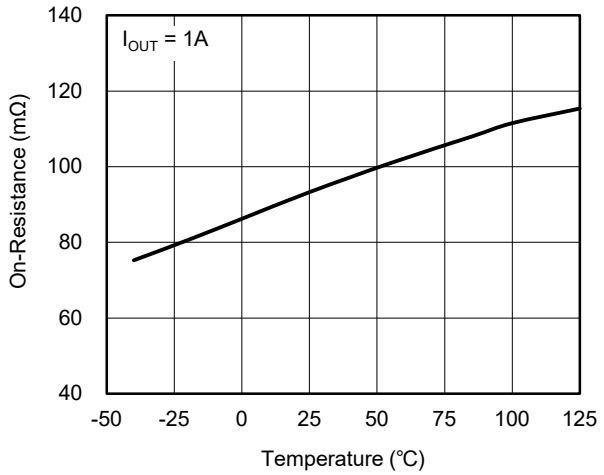
Phase B Current Sense Ratio vs. Temperature



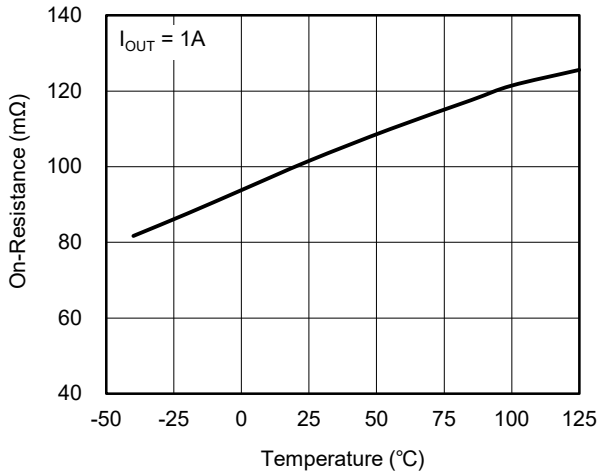
Phase C Current Sense Ratio vs. Temperature



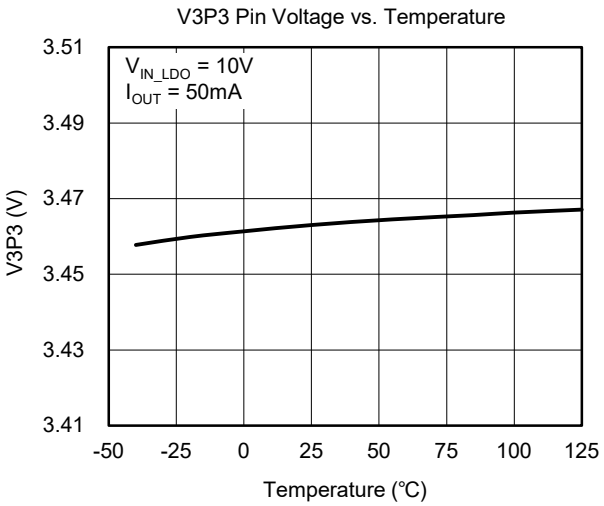
HS FET On-Resistance vs. Temperature



LS FET On-Resistance vs. Temperature

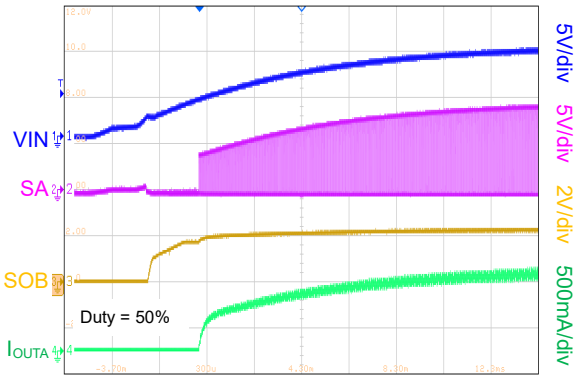


TYPICAL PERFORMANCE CHARACTERISTICS (continued)



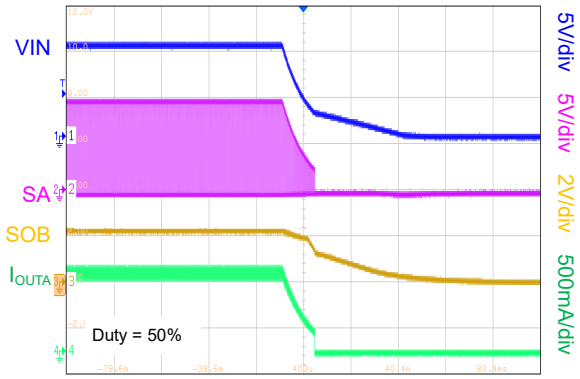
T_A = +25℃, V_{IN} = 10V, V_{REF} = V3P3, SOB with 5kΩ divide, output with 5Ω + 1mH load, unless otherwise noted.

Power Ramp-Up



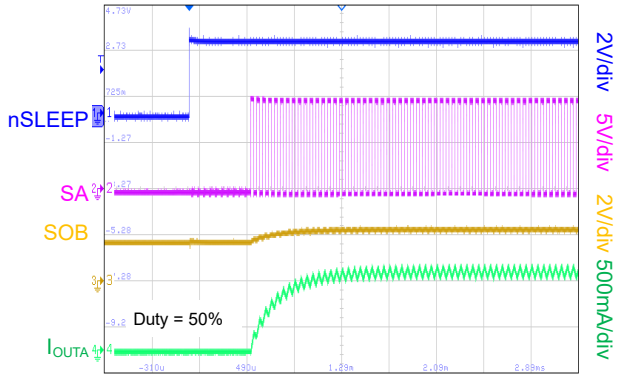
Time (2ms/div)

Power Ramp-Down



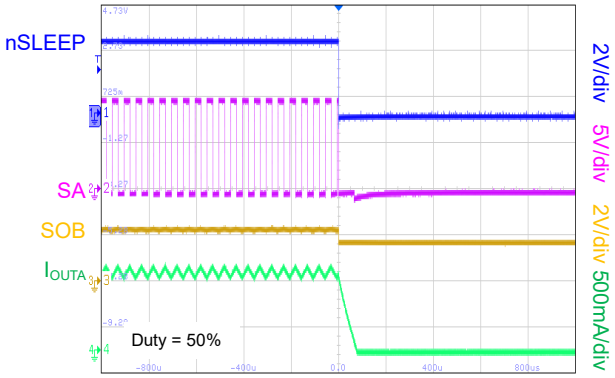
Time (20ms/div)

Sleep Recovery



Time (400μs/div)

Sleep Entry

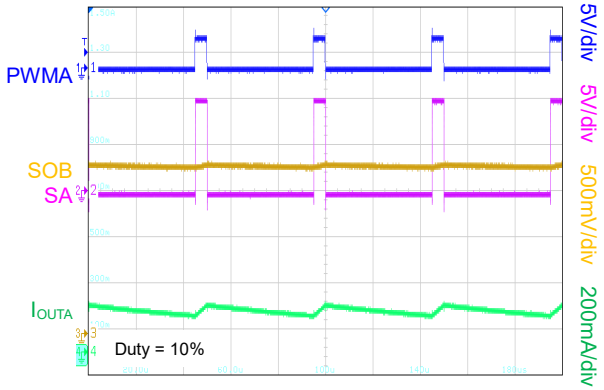


Time (200μs/div)

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

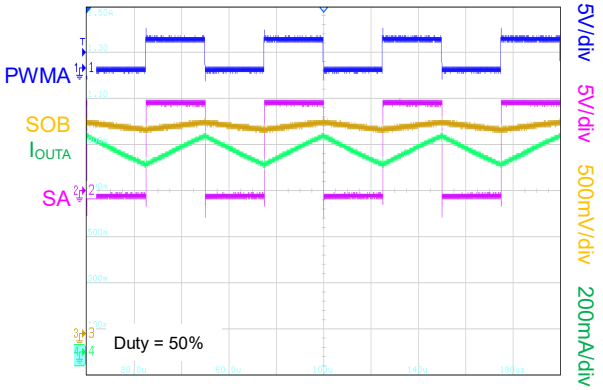
T_A = +25℃, V_{IN} = 10V, V_{REF} = V3P3, SOB with 5kΩ divide, output with 5Ω + 1mH load, unless otherwise noted.

Steady State



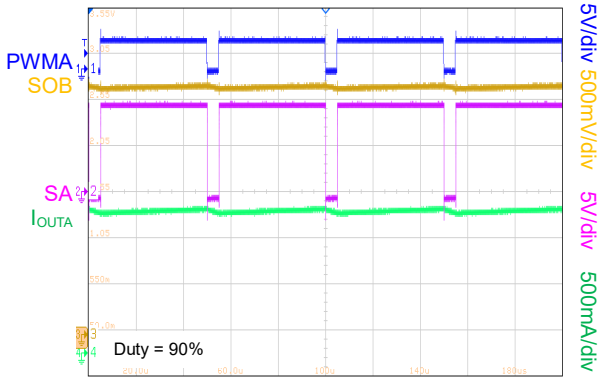
Time (20μs/div)

Steady State



Time (20μs/div)

Steady State



Time (20μs/div)

FUNCTIONAL BLOCK DIAGRAM

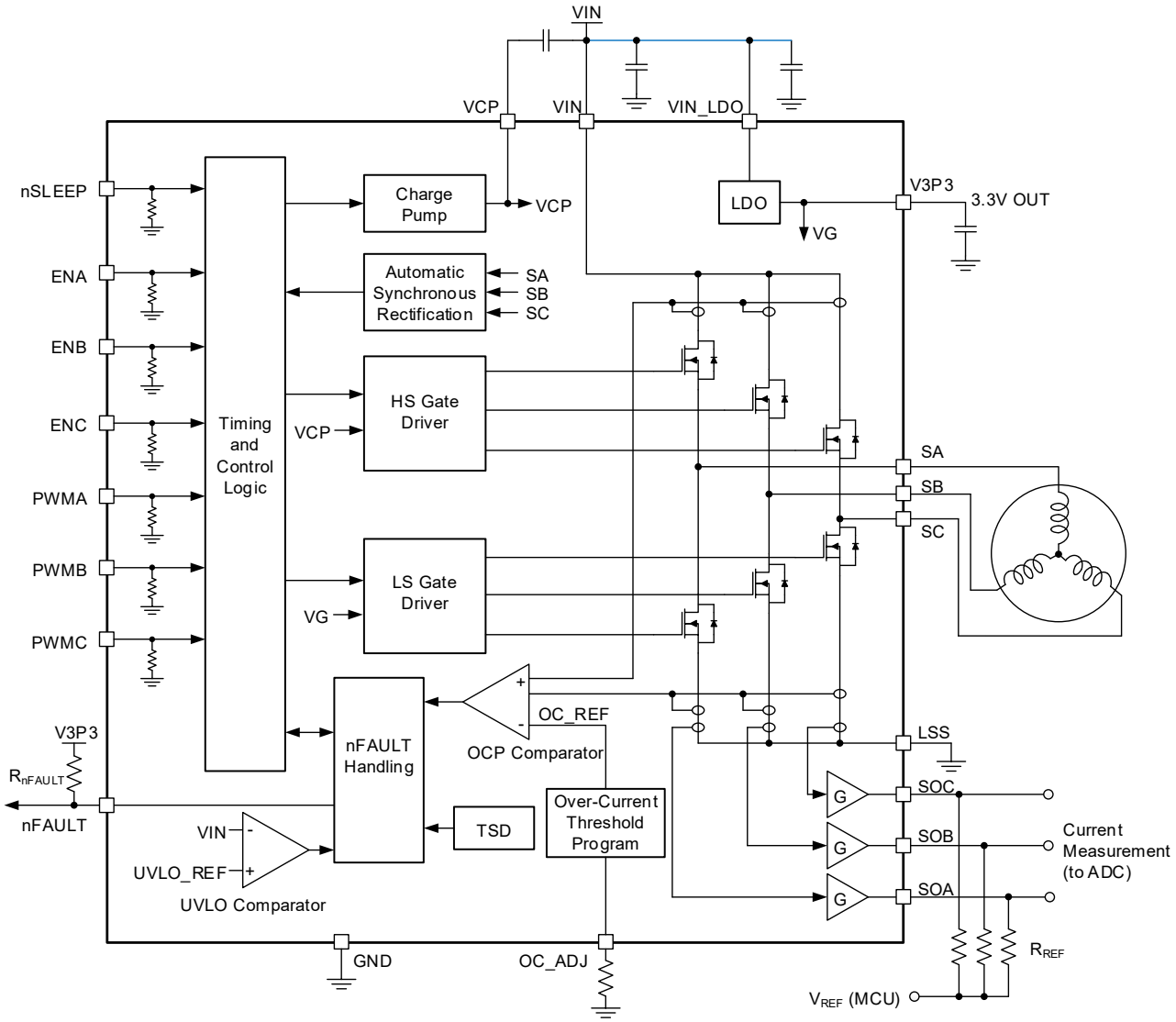


Figure 2. Block Diagram

DETAILED DESCRIPTION

The SGM42560Q is an integrated 185mΩ (combination of HS and LS FETs on-resistance) driver for three-phase BLDC motor drive applications. The device reduces system component counts, cost and complexity by integrating three half-bridge FETs, current sensing and protection circuits.

Input Logic

Please refer to SGM42560Q input control logic in Table 1.

Table 1. Truth Table of SGM42560Q

ENx	PWMx	Sx
H	H	VIN
H	L	GND
L	X	Hi-Z

nSLEEP Operation

This active-low input is used to minimize power consumption when the device is not in use. Sleep mode disables most of the internal circuitry, including the output FETs and charge pump. nSLEEP logic-high allows normal operation. It is recommended to apply PWM signals at least 4ms after the nSLEEP is pulled high to allow the charge pump ramp-up. The nSLEEP input is pull-down internally.

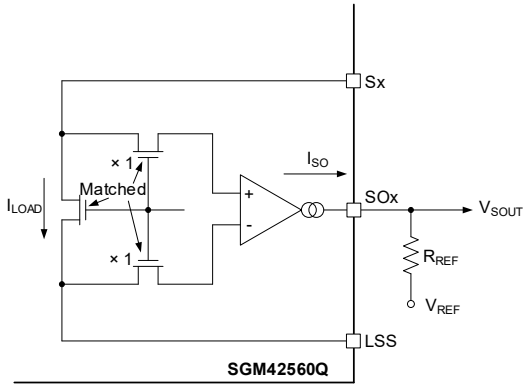
Current Sense Amplifiers

The SGM42560Q integrates three high performance LS current sense amplifiers for current measurements using built-in current sensing. LS current measurements are commonly used to implement over-current protection, external torque control, or brushless DC commutation with an external controller. All three amplifiers can be used to sense the current in each of the half-bridge legs (LS FETs). Each half-bridge has its own current sensing output (SOx) for sensing the sink or source current flowing through the low-side FET (bi-direction). Connect a resistor (R_{REF}) from SOx to reference voltage will convert the current into a voltage output. Please refer to the Equation 1 for calculation of current and SOx output voltage:

$$V_{SOUT} = V_{REF} + (R_{REF} \times I_{LOAD})/4000 \quad (1)$$

When using an ADC with inputs that are ratio-metric to its supply voltage, the SOx output is connected to the ADC reference power supply and GND through two resistors of the same value. The SOx output will be half of the ADC reference voltage when the current is zero.

Please refer to simplified schematic of the current measurement in Figure 3.



$I_{SO} = I_{LOAD}/4000$

$V_{SOUT} = V_{REF} + (I_{SO} \times R_{REF}) = V_{REF} + ((I_{LOAD} \times R_{REF})/4000)$

Figure 3. Current Measurement Circuit Diagram

Automatic Synchronous Rectification

The SGM42560Q has automatic synchronous rectification feature (active demagnetization) which reduces power losses in device by reducing body-diode conduction losses. If both half-bridge power FETs are turned off, then the automatic synchronous rectification applies, the inductor current decays through FETs instead of the body-diodes.

The SGM42560Q includes a HS output comparator and a LS output comparator for each half-bridge channel, which detect the respective body-diodes' current flow. The HS output comparator compares the half-bridge output voltage with respect to V_{IN}. The LS output comparator compares the half-bridge output voltage with respect to LSS. When both HS FET and LS FET of a channel are turned off, upon the flow of the recirculation current: if the LS body-diode conducts, the half-bridge output voltage is driven below LSS, and the LS output comparator trips, then the LS FET will be on until the recirculation current reduces to zero. Similarly, if the HS body-diode conducts, the half-bridge output voltage is driven above V_{IN}, and the HS output comparator trips, then the HS FET is turned on until the current flowing through it reduces to zero.

nFAULT Output

The nFAULT is an open-drain output that needs to be pulled up externally. The nFAULT will be pulled low in OC (over-current) or TSD (thermal shutdown) condition.

DETAILED DESCRIPTION (continued)

UVLO Protection

At any time, the V_{IN} power supply falls below the V_{UVLO} threshold (V_{IN} falling threshold), all of the integrated FETs, driver charge pump and digital logic controller are disabled and the internal logic is reset. The device will resume normal operation when power supply goes higher than V_{UVLO} threshold.

Thermal Shutdown (TSD)

All bridges and drivers are shutdown if a junction over-temperature occurs in the device and the nFAULT will be pulled low. Once the temperature goes back to the safe level, the device resumes its operation.

Over-Current Protection

A MOSFET over-current event is sensed by monitoring the current flowing through the FETs. If the current across a FET exceeds the I_{OCP} threshold (refer to Table 2 for setup) for longer than the t_{OCD} deglitch time, all the three half-bridges will be disabled (shutdown), and the nFAULT pin will be driven low. The over-current shutdown is latched until either nSLEEP is reset or VIN is power-cycled.

An over-current may occur due to a short between a switching node and ground or to the VIN supply line, or to the other node of the bridge (a winding short). Figure 4 shows a simplified diagram of the OCP circuit for one output.

Table 2. Over-Current Threshold

OC_ADJ Resistor Value	OCP Threshold (TYP)
0Ω	3.5A
Floating	6.0A

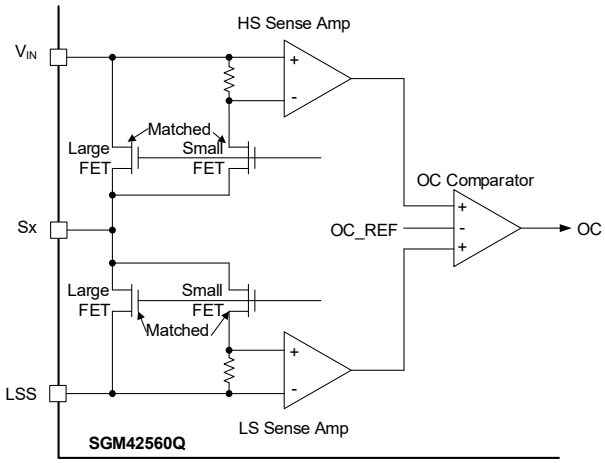


Figure 4. OCP Circuit

3.3V LDO Output

A 3.3V LDO regulator is provided to power internal logic and external circuitry, such as the hall effect sensors or microcontroller, whose output capability is 50mA. A bypass capacitor between V3P3 pin and GND is required. The recommended value for the bypass capacitor is 4.7μF to 10μF.

Charge Pump

The charge pump is used to generate a gate supply which is greater than V_{IN} to turn on the high-side FETs. A 1μF (10V or higher) ceramic capacitor is required between VIN and VCP pins.

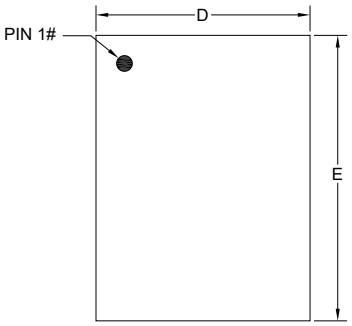
REVISION HISTORY

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

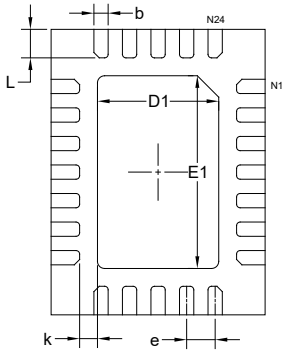
Changes from Original to REV.A (MARCH 2026)	Page
Changed from product preview to production data	All

PACKAGE OUTLINE DIMENSIONS

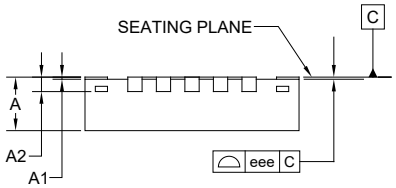
TQFN-3×4-24L



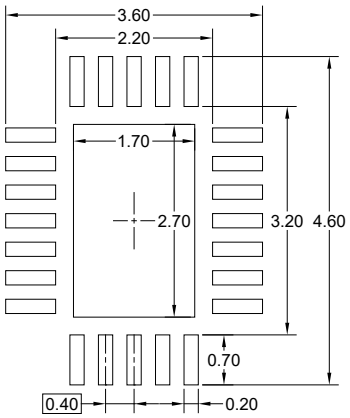
TOP VIEW



BOTTOM VIEW



SIDE VIEW



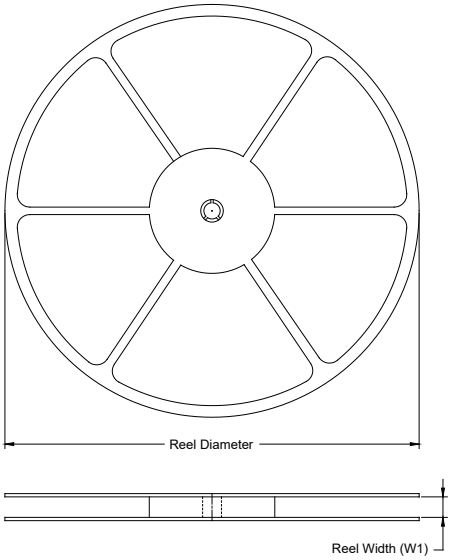
RECOMMENDED LAND PATTERN (Unit: mm)

Symbol	Dimensions In Millimeters		
	MIN	NOM	MAX
A	0.700	0.750	0.800
A1	0.000	-	0.050
A2		0.203 REF	
b	0.150	0.200	0.250
D	2.900	3.000	3.100
E	3.900	4.000	4.100
D1	1.600	1.700	1.800
E1	2.600	2.700	2.800
k		0.250 REF	
L	0.300	0.400	0.500
e		0.400 BSC	
eee		0.080	

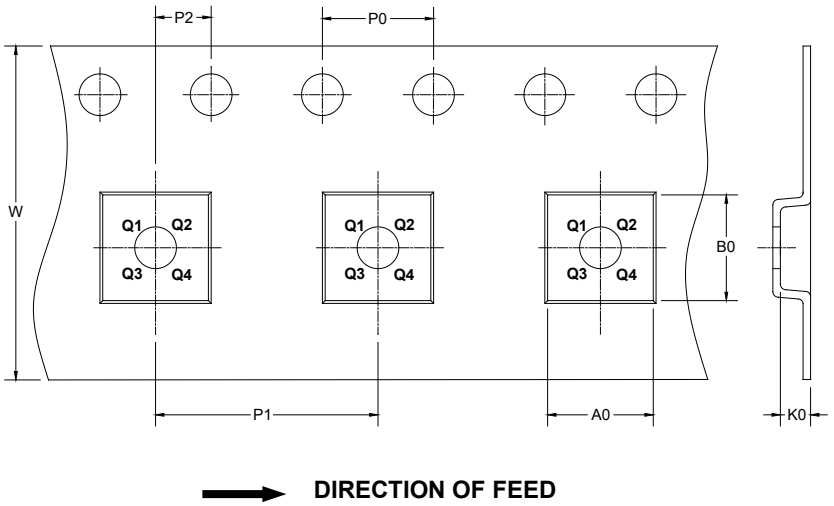
NOTE: This drawing is subject to change without notice.

TAPE AND REEL INFORMATION

REEL DIMENSIONS



TAPE DIMENSIONS



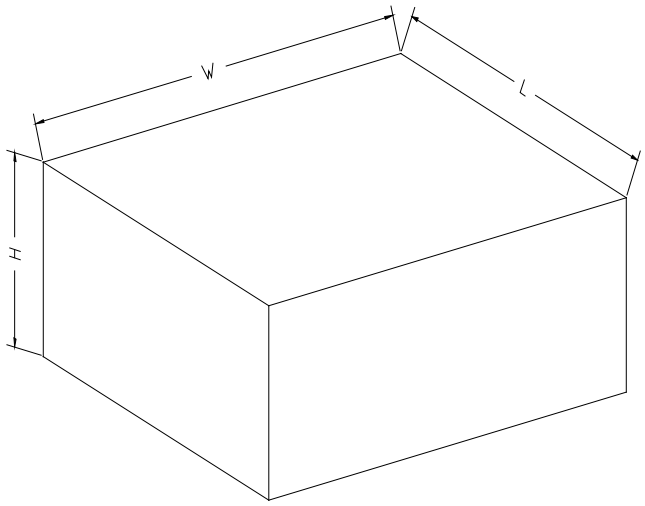
NOTE: The picture is only for reference. Please make the object as the standard.

KEY PARAMETER LIST OF TAPE AND REEL

Package Type	Reel Diameter	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P0 (mm)	P1 (mm)	P2 (mm)	W (mm)	Pin1 Quadrant
TQFN-3×4-24L	13″	12.4	3.40	4.40	1.10	4.0	8.0	2.0	12.0	Q1

DD0001

CARTON BOX DIMENSIONS



NOTE: The picture is only for reference. Please make the object as the standard.

KEY PARAMETER LIST OF CARTON BOX

Reel Type	Length (mm)	Width (mm)	Height (mm)	Pizza/Carton
13″	386	280	370	5

DD0002